

N-channel 650 V, 0.42 Ω typ., 8 A MDmesh™ M2 Power MOSFET in a TO-220 package

Datasheet - production data

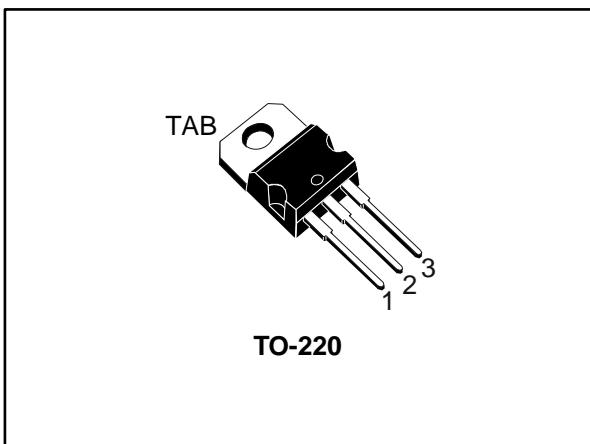
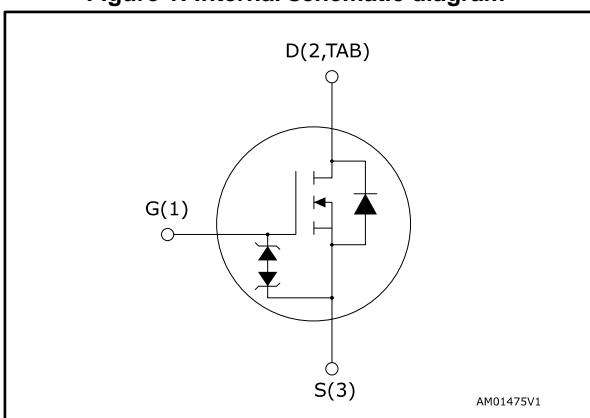


Figure 1: Internal schematic diagram



Features

| Order code | V _{DS} | R _{DS(on)} max. | I _D |
|------------|-----------------|--------------------------|----------------|
| STP12N65M2 | 650 V | 0.50 Ω | 8 A |

- Extremely low gate charge
- Excellent output capacitance (C_{oss}) profile
- 100% avalanche tested
- Zener-protected

Applications

- Switching applications

Description

This device is an N-channel Power MOSFET developed using MDmesh™ M2 technology. Thanks to its strip layout and an improved vertical structure, the device exhibits low on-resistance and optimized switching characteristics, rendering it suitable for the most demanding high efficiency converters.

Table 1: Device summary

| Order code | Marking | Package | Packing |
|------------|---------|---------|---------|
| STP12N65M2 | 12N65M2 | TO-220 | Tube |

Contents

| | | |
|----------|--|-----------|
| 1 | Electrical ratings | 3 |
| 2 | Electrical characteristics | 4 |
| 2.1 | Electrical characteristics (curves)..... | 6 |
| 3 | Test circuits | 8 |
| 4 | Package information | 9 |
| 4.1 | TO-220 type A package information..... | 10 |
| 5 | Revision history | 12 |

1 Electrical ratings

Table 2: Absolute maximum ratings

| Symbol | Parameter | Value | Unit |
|----------------|--|------------|------------------|
| V_{GS} | Gate-source voltage | ± 25 | V |
| I_D | Drain current (continuous) at $T_{case} = 25^\circ\text{C}$ | 8 | A |
| | Drain current (continuous) at $T_{case} = 100^\circ\text{C}$ | 5 | |
| $I_{DM}^{(1)}$ | Drain current (pulsed) | 32 | A |
| P_{TOT} | Total dissipation at $T_{case} = 25^\circ\text{C}$ | 85 | W |
| $dv/dt^{(2)}$ | Peak diode recovery voltage slope | 15 | V/ns |
| $dv/dt^{(3)}$ | MOSFET dv/dt ruggedness | 50 | |
| T_{stg} | Storage temperature range | -55 to 150 | $^\circ\text{C}$ |
| T_j | Operating junction temperature range | | |

Notes:

(1) Pulse width is limited by safe operating area.

(2) $I_{SD} \leq 8$ A, $di/dt = 400$ A/ μs , $V_{DS(\text{peak})} < V_{(\text{BR})DSS}$, $V_{DD} = 400$ V

(3) $V_{DS} \leq 520$ V

Table 3: Thermal data

| Symbol | Parameter | Value | Unit |
|----------------|-------------------------------------|-------|---------------------------|
| $R_{thj-case}$ | Thermal resistance junction-case | 1.47 | $^\circ\text{C}/\text{W}$ |
| $R_{thj-amb}$ | Thermal resistance junction-ambient | 62.5 | |

Table 4: Avalanche characteristics

| Symbol | Parameter | Value | Unit |
|----------|---|-------|------|
| I_{AR} | Avalanche current, repetitive or non-repetitive (pulse width limited by $T_{j\max.}$) | 1.6 | A |
| E_{AS} | Single pulse avalanche energy (starting $T_j = 25^\circ\text{C}$, $I_D = I_{AR}$, $V_{DD} = 50$ V) | 250 | mJ |

2 Electrical characteristics

($T_{case} = 25^\circ C$ unless otherwise specified)

Table 5: Static

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|---------------|-----------------------------------|--|------|------|----------|----------|
| $V_{(BR)DSS}$ | Drain-source breakdown voltage | $V_{GS} = 0 V, I_D = 1 mA$ | 650 | | | V |
| I_{DSS} | Zero-gate voltage drain current | $V_{GS} = 0 V, V_{DS} = 650 V$ | | | 1 | μA |
| | | $V_{GS} = 0 V, V_{DS} = 650 V, T_{case} = 125^\circ C^{(1)}$ | | | 100 | |
| I_{GSS} | Gate-body leakage current | $V_{DS} = 0 V, V_{GS} = \pm 25 V$ | | | ± 10 | μA |
| $V_{GS(th)}$ | Gate threshold voltage | $V_{DS} = V_{GS}, I_D = 250 \mu A$ | 2 | 3 | 4 | V |
| $R_{DS(on)}$ | Static drain-source on-resistance | $V_{GS} = 10 V, I_D = 4 A$ | | 0.42 | 0.50 | Ω |

Notes:

⁽¹⁾Defined by design, not subject to production test.

Table 6: Dynamic

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|----------------------|-------------------------------|--|------|------|------|----------|
| C_{iss} | Input capacitance | $V_{DS} = 100 V, f = 1 MHz, V_{GS} = 0 V$ | - | 535 | - | pF |
| C_{oss} | Output capacitance | | - | 25 | - | |
| C_{rss} | Reverse transfer capacitance | | - | 1.1 | - | |
| $C_{oss\ eq.}^{(1)}$ | Equivalent output capacitance | $V_{DS} = 0$ to $520 V, V_{GS} = 0 V$ | - | 144 | - | pF |
| R_G | Intrinsic gate resistance | $f = 1 MHz, I_D = 0 A$ | - | 7 | - | Ω |
| Q_g | Total gate charge | $V_{DD} = 520 V, I_D = 8 A, V_{GS} = 0$ to $10 V$ (see Figure 15: "Test circuit for gate charge behavior") | - | 16.7 | - | nC |
| Q_{gs} | Gate-source charge | | - | 2.6 | - | |
| Q_{gd} | Gate-drain charge | | - | 8.6 | - | |

Notes:

⁽¹⁾ $C_{oss\ eq.}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS} .

Table 7: Switching times

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|--------------|---------------------|---|------|------|------|------|
| $t_{d(on)}$ | Turn-on delay time | $V_{DD} = 325 V, I_D = 4 A$ $R_G = 4.7 \Omega, V_{GS} = 10 V$ (see Figure 14: "Test circuit for resistive load switching times" and Figure 19: "Switching time waveform") | - | 9 | - | ns |
| t_r | Rise time | | - | 7 | - | |
| $t_{d(off)}$ | Turn-off delay time | | - | 34 | - | |
| t_f | Fall time | | - | 13.5 | - | |

Table 8: Source-drain diode

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|-----------------|-------------------------------|---|------|------|------|---------------|
| $I_{SD}^{(1)}$ | Source-drain current | | - | | 8 | A |
| $I_{SDM}^{(2)}$ | Source-drain current (pulsed) | | - | | 32 | A |
| $V_{SD}^{(3)}$ | Forward on voltage | $V_{GS} = 0 \text{ V}$, $I_{SD} = 8 \text{ A}$ | - | | 1.6 | V |
| t_{rr} | Reverse recovery time | $I_{SD} = 8 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}$, $V_{DD} = 60 \text{ V}$ (see <i>Figure 16: "Test circuit for inductive load switching and diode recovery times"</i>) | - | 313 | | ns |
| Q_{rr} | Reverse recovery charge | | - | 2.7 | | μC |
| I_{RRM} | Reverse recovery current | | - | 17 | | A |
| t_{rr} | Reverse recovery time | $I_{SD} = 8 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}$, $V_{DD} = 60 \text{ V}$, $T_j = 150 \text{ }^\circ\text{C}$ (see <i>Figure 16: "Test circuit for inductive load switching and diode recovery times"</i>) | - | 462 | | ns |
| Q_{rr} | Reverse recovery charge | | - | 4.1 | | μC |
| I_{RRM} | Reverse recovery current | | - | 17.5 | | A |

Notes:

(1) Limited by package.

(2) Pulse width is limited by safe operating area.

(3) Pulse test: pulse duration = 300 μs , duty cycle 1.5%.

2.1 Electrical characteristics (curves)

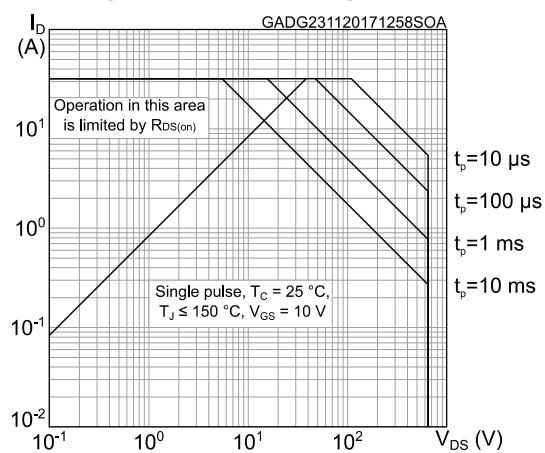
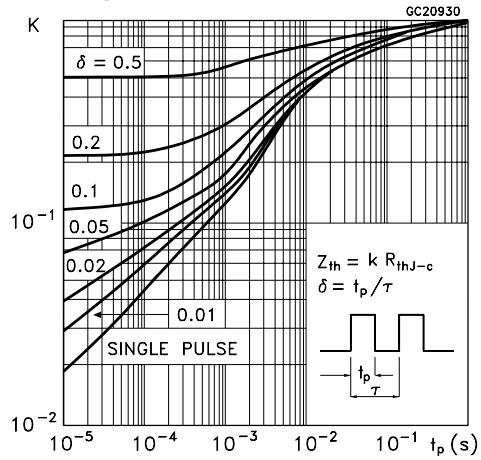
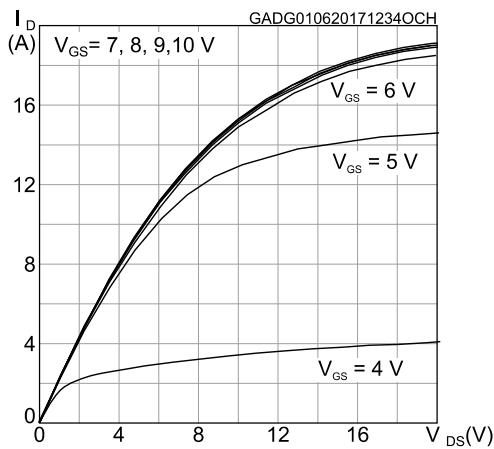
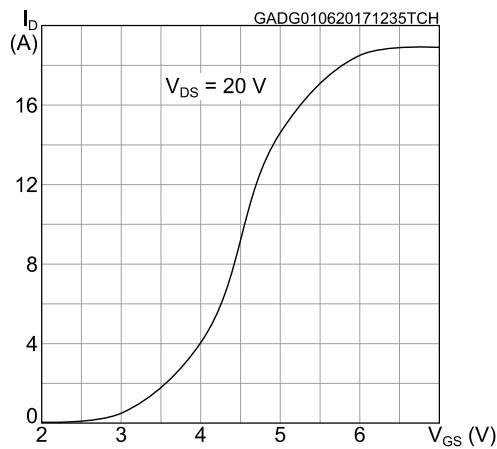
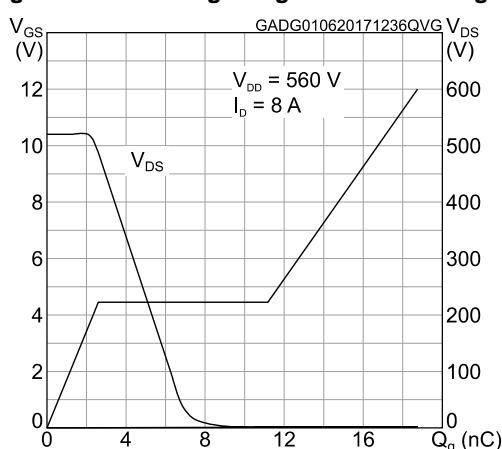
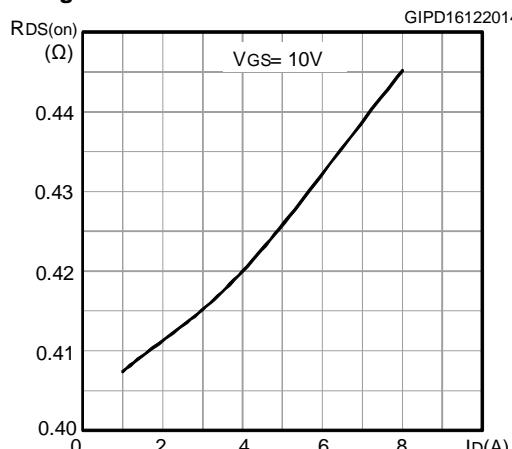
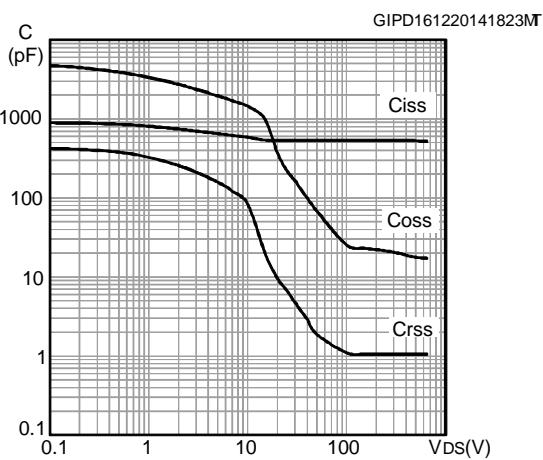
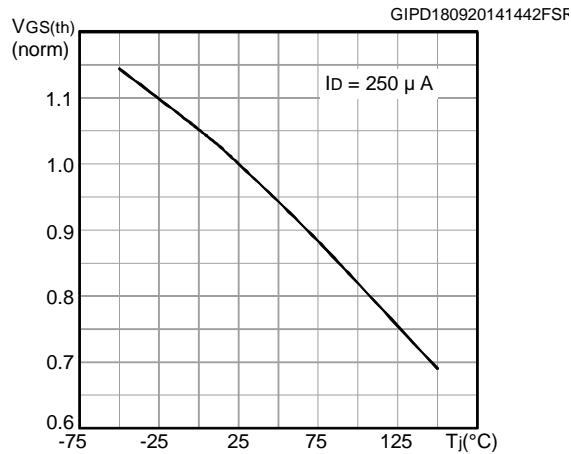
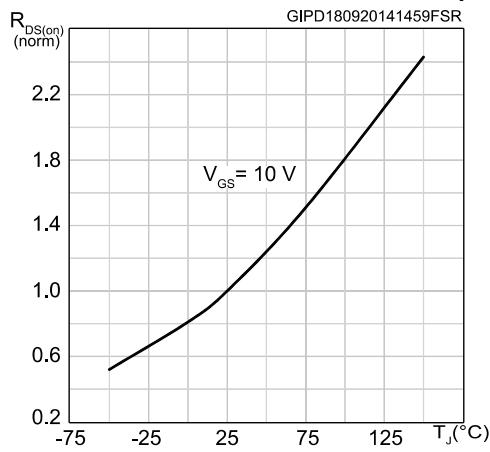
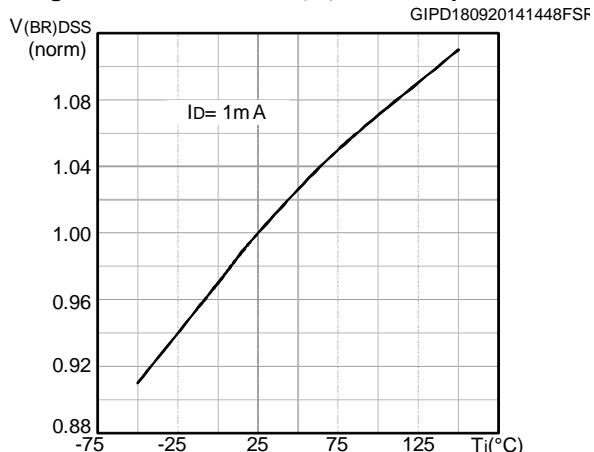
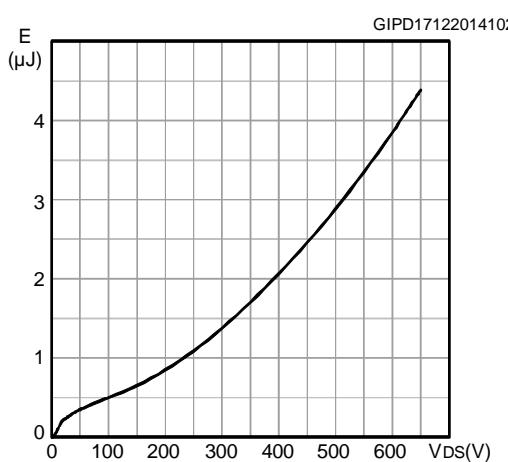
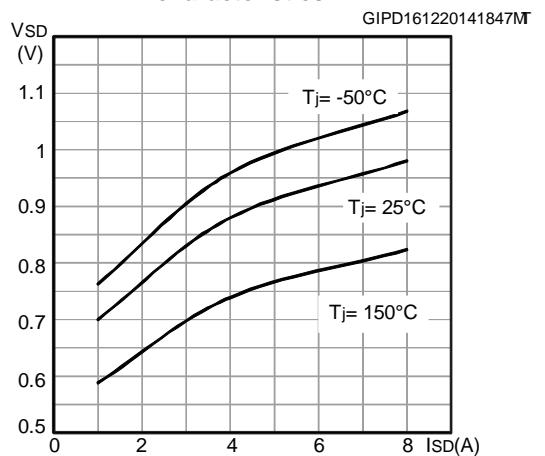
Figure 2: Safe operating area**Figure 3: Thermal impedance****Figure 4: Output characteristics****Figure 5: Transfer characteristics****Figure 6: Gate charge vs gate-source voltage****Figure 7: Static drain-source on-resistance**

Figure 8: Capacitance variations**Figure 9: Normalized gate threshold voltage vs temperature****Figure 10: Normalized on-resistance vs temperature****Figure 11: Normalized V_{(BR)DSS} vs temperature****Figure 12: Output capacitance stored energy****Figure 13: Source-drain diode forward characteristics**

3 Test circuits

Figure 14: Test circuit for resistive load switching times

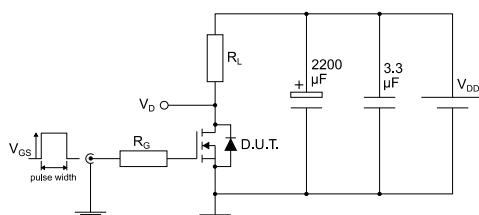


Figure 15: Test circuit for gate charge behavior

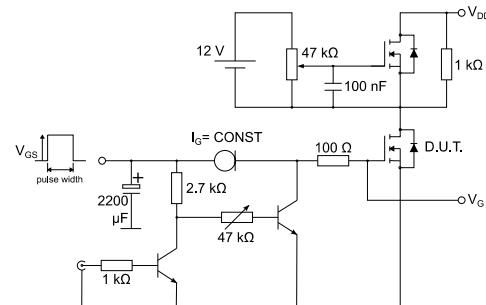


Figure 16: Test circuit for inductive load switching and diode recovery times

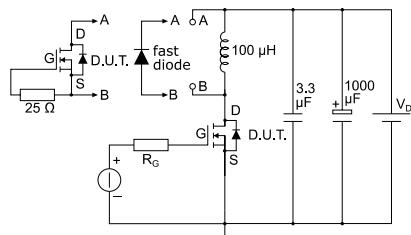


Figure 17: Unclamped inductive load test circuit

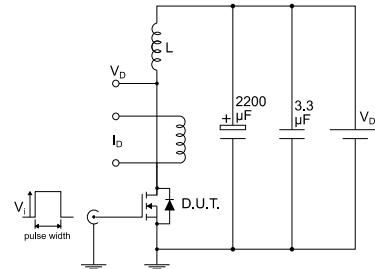


Figure 18: Unclamped inductive waveform

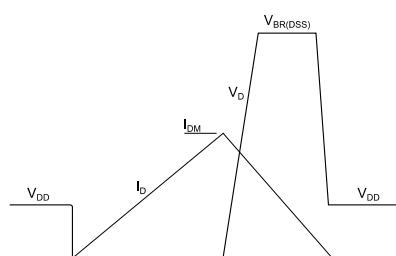
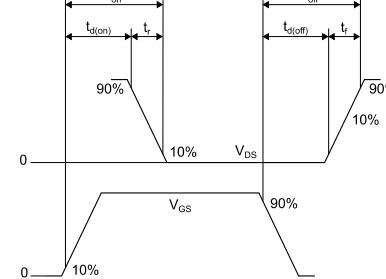


Figure 19: Switching time waveform



4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com.
ECOPACK® is an ST trademark.

4.1 TO-220 type A package information

Figure 20: TO-220 type A package outline

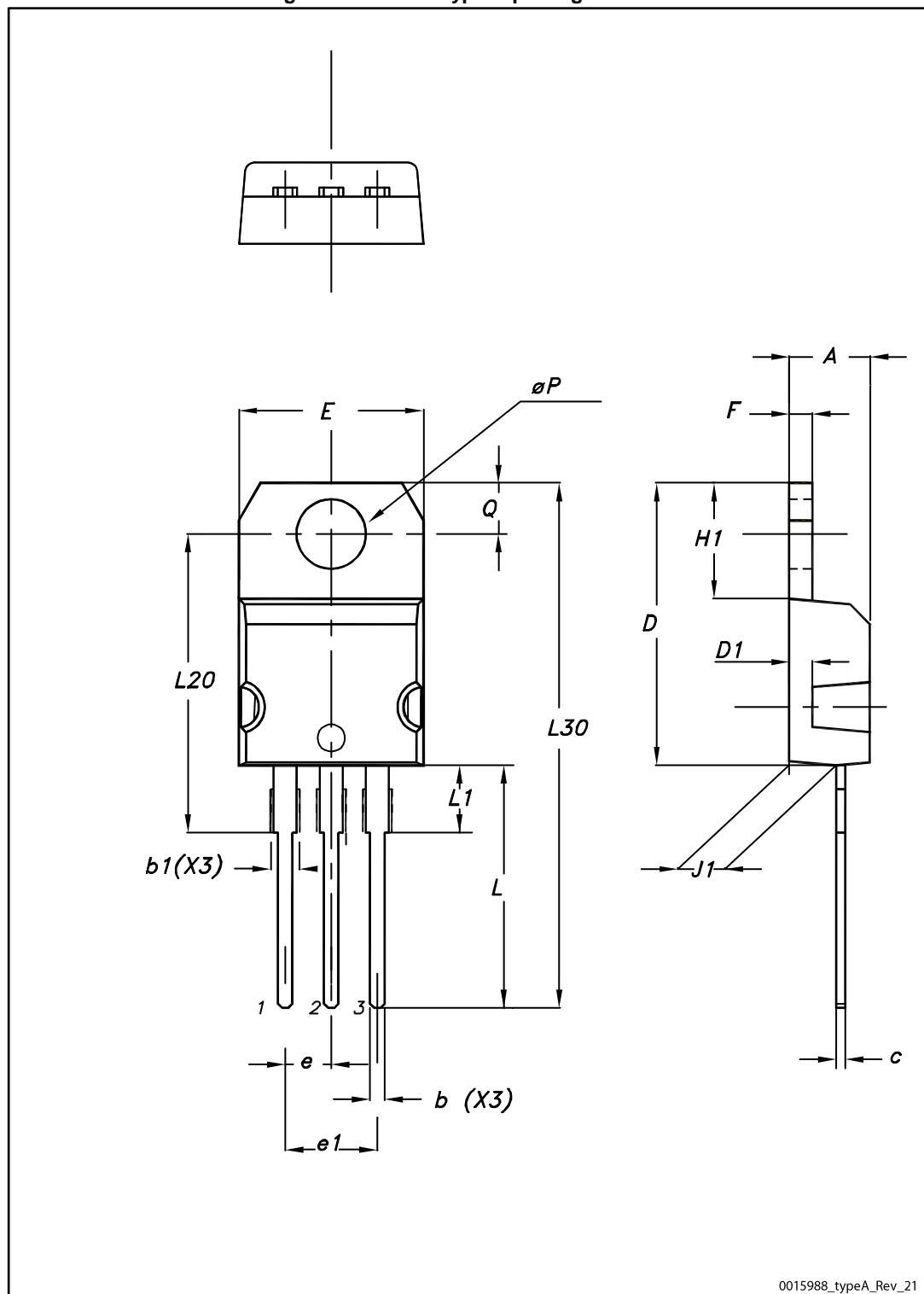


Table 9: TO-220 type A package mechanical data

| Dim. | mm | | |
|------|-------|-------|-------|
| | Min. | Typ. | Max. |
| A | 4.40 | | 4.60 |
| b | 0.61 | | 0.88 |
| b1 | 1.14 | | 1.55 |
| c | 0.48 | | 0.70 |
| D | 15.25 | | 15.75 |
| D1 | | 1.27 | |
| E | 10.00 | | 10.40 |
| e | 2.40 | | 2.70 |
| e1 | 4.95 | | 5.15 |
| F | 1.23 | | 1.32 |
| H1 | 6.20 | | 6.60 |
| J1 | 2.40 | | 2.72 |
| L | 13.00 | | 14.00 |
| L1 | 3.50 | | 3.93 |
| L20 | | 16.40 | |
| L30 | | 28.90 | |
| øP | 3.75 | | 3.85 |
| Q | 2.65 | | 2.95 |

5 Revision history

Table 10: Document revision history

| Date | Revision | Changes |
|-------------|----------|---------------|
| 28-Nov-2017 | 1 | First release |

IMPORTANT NOTICE – PLEASE READ CAREFULLY

STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, enhancements, modifications, and improvements to ST products and/or to this document at any time without notice. Purchasers should obtain the latest relevant information on ST products before placing orders. ST products are sold pursuant to ST's terms and conditions of sale in place at the time of order acknowledgement.

Purchasers are solely responsible for the choice, selection, and use of ST products and ST assumes no liability for application assistance or the design of Purchasers' products.

No license, express or implied, to any intellectual property right is granted by ST herein.

Resale of ST products with provisions different from the information set forth herein shall void any warranty granted by ST for such product.

ST and the ST logo are trademarks of ST. All other product or service names are the property of their respective owners.

Information in this document supersedes and replaces information previously supplied in any prior versions of this document.

© 2017 STMicroelectronics – All rights reserved